



<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/532,424	FUJII ET AL.	
	Examiner	Art Unit	
	Steven D. Maki	1733	

SEARCHED			
Class	Subclass	Date	Examiner
152	154.2		
	209.17		
156	110.1		
73	146		
29	402.03		
	426.1		
updated	above	6/24/2007	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
none	6/24/2007	